Notice of References Cited

Application/Control No. 10/019,201

Applicant(s)/Patent Under Reexamination MAENO ET AL.

Examiner

Art Unit Chris C. Chu 2815

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6417532 - B2	07-2002	Tsunoda et al.	257/219
	В	US-6353258 - B1	03-2002	Inoue et al.	257/723
	С	US-6297549 - B1	10-2001	Hiyoshi	257/703
	D	US-6272015 - B1	08-2001	Mangtani .	361/707
	E	US-6215679 - B1	04-2001	Yamane et al.	363/132
	F	US-5926372 - A	07-1999	Rinehart et al.	361/704
	G	US-			
	Н	US-			
	_	US-			
	J	US-			
	К	US-	-		
	L	US-			-
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP - 2001237369 - A	08-2001	Japan	Polack et al.	
	0					
	Р					
	α					
	R					
	S					
	۲				·	

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.